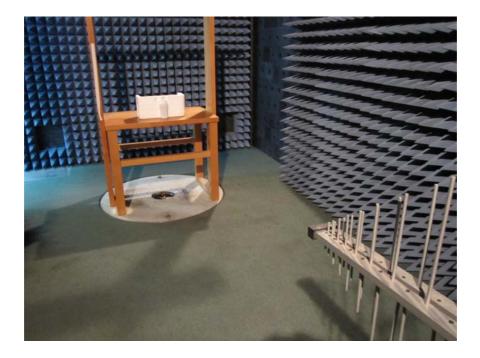


Photograph No.1 Setup for spurious emission field strength measurements in the anechoic chamber below 30 MHz



Photograph No.2 Setup for hopping frequencies and spurious emission field strength measurements in the anechoic chamber in 30 – 1000 MHz range



Photograph No.3 Setup for spurious emission field strength measurements in the anechoic chamber above 1000 MHz range



Photograph No.4 Setup for spurious emission field strength measurements in the anechoic chamber, EUT close view



Photograph No.5 Setup for carrier field strength measurements at the OATS in 30 – 1000 MHz range, EUT in X-axis position



Photograph No.6 Setup for carrier field strength measurements at the OATS in 30 – 1000 MHz range, EUT in Y-axis position



Photograph No.7 Setup for carrier field strength measurements at the OATS in 30 – 1000 MHz range, EUT in Z-axis position



Photograph No.8 Setup for OBW measurements





Photograph No.9 Setup for band edge emissions and hopping parameters measurements